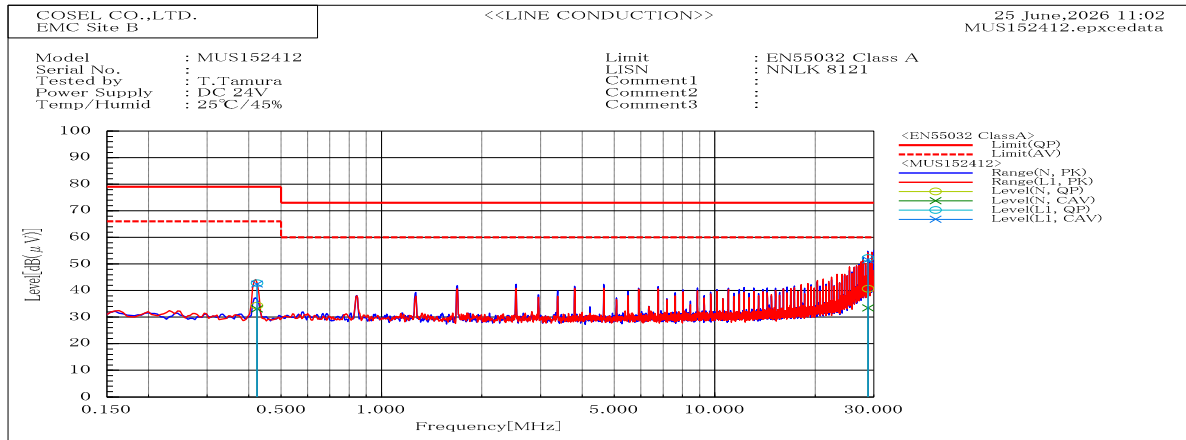
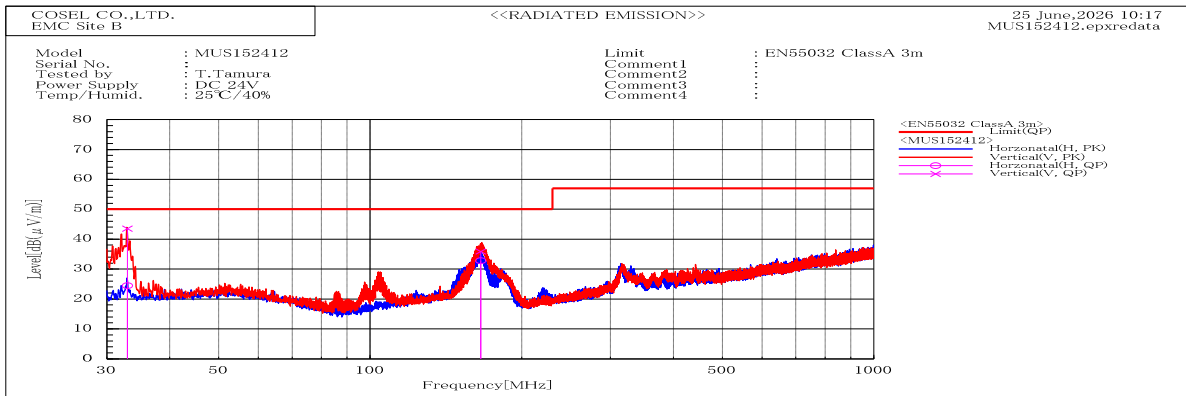


DATA SHEET		Date	26-Jun-26
Model	MUS152412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Tamura



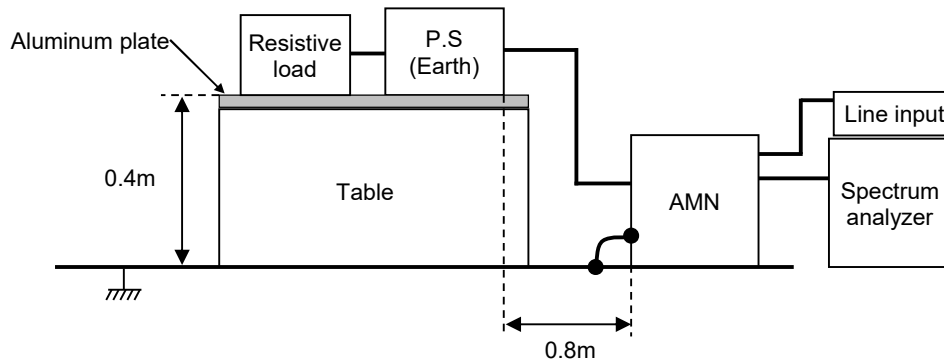
Frequency [MHz]	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.423	L1	42.8	42.5	79	66	36.2	23.5	Pass	
28.799	L1	52.3	51.5	73	60	20.7	8.5	Pass	
0.423	N	34.3	33.1	79	66	44.7	32.9	Pass	
28.79	N	40.7	33.5	73	60	32.3	26.5	Pass	



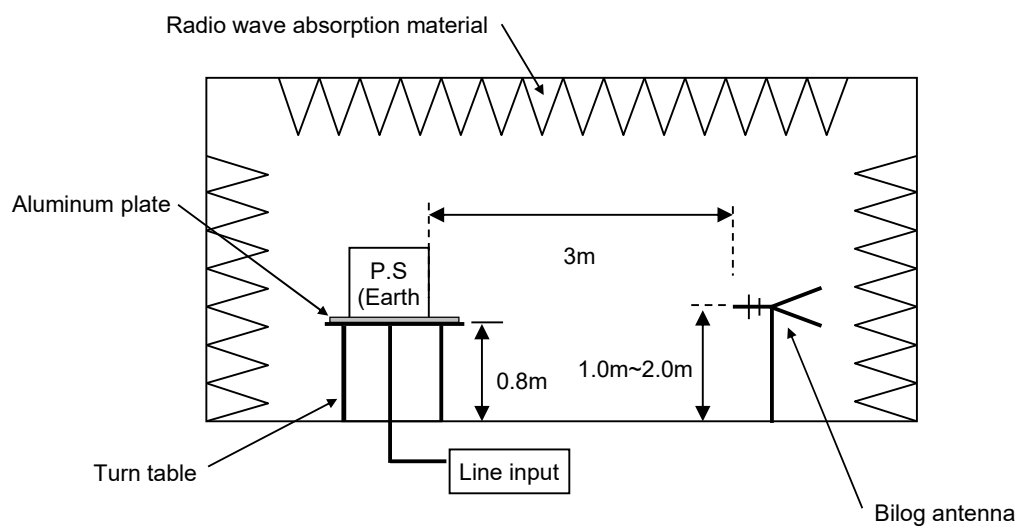
Frequency [MHz]	Polarization	Stability	Level dB(μV/m)		Limit dB(μV/m)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV	QP	AV					
32.964	H	Stable	24.5		50		25.5	Pass	100	9.1	
32.978	V	Stable	43.5		50		6.5	Pass	100	72.9	
165.747	H	Stable	32.8		50		17.2	Pass	168.2	9.2	
165.802	V	Stable	35.8		50		14.2	Pass	101.7	351.5	

DATA SHEET		Date	26-Jun-26
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Tamura

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
Model Name: MUS15□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

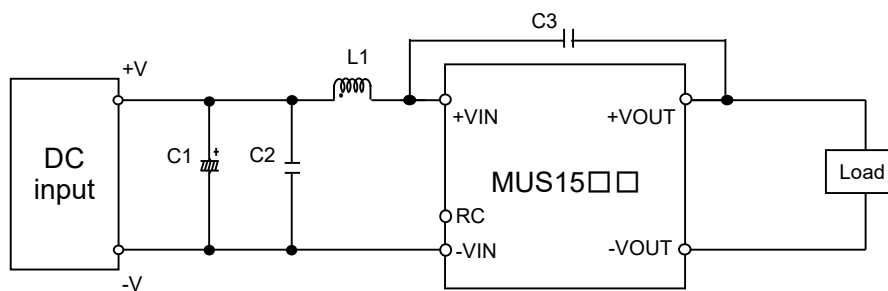


Fig.1 MUS15□□ Testing circuitry

C1 :	MUS1524□	50V 47 μ F Electric capacitor (UPWseries NICHICON)
	MUS1548□	-
C2 :	MUS1524□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS1548□	100V 2.2 μ F Ceramic capacitor (C3216X7S2A225KT TDK)
C3 :	MUS15□□	2000V 1000pF Ceramic capacitor (C3225X7S3D102K200AA TDK)
L1 :	MUS1524□	1600mA 22 μ H Inductor (LQH5BPN220M38 MURATA MANUFACTURING)
	MUS1548□	1100mA 47 μ H Inductor (LQH5BPN470M38 MURATA MANUFACTURING)